

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/788,578	NGUYEN, ANDREW P.	
		Examiner	Art Unit	Page 1 of 1
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	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 2001205162 A	07-2001	Japan	MATSUO et al.	B05C 05/02
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**NON-PATENT DOCUMENTS**

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	U	English Translated Abstract and Detailed Description of JP-2001-205162A
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.